

1. Record Nr.	UNISA996308768403316
Titolo	Fifth Size Strain Conference. Diffraction Analysis of the Microstructure of Materials : Garmisch-Partenkirchen, October 7-9, 2007
Pubbl/distr/stampa	De Gruyter, 2008 Berlin ; ; Boston : , : Oldenbourg Wissenschaftsverlag, , [2015] ©2008
ISBN	3-486-99256-2
Descrizione fisica	1 online resource (xii, 305 pages) : illustrations
Collana	Zeitschrift für Kristallographie / Supplemente ; ; 27
Soggetti	Cosmic physics Geophysics
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Bibliographic Level Mode of Issuance: Monograph
Nota di bibliografia	Includes bibliographical references.
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